

PN CHECKER

PN-12 α PN CHECKER



- Single-Point, Contact Type
- Conductivity type (P/N) checker by Contact thermo-electromotive force method (seebek effect)
- Thermo electrode and cold electrode are mounted on detecting part of measuring probes
- 2 types of probes available for selection;
 - ✓ 2 probe ver (Hot probe, Cold probe)
 - ✓ 1 probe ver (Hot & Cold probe)
- **Sample Size:** at least 2"
- **Resistivity Range (Ω .cm):** 1m to 20k

APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC etc)
- Single crystalline silicon wafer, bulk, ingot

PN-50 α PN CHECKER

- Single Point, Non-contact conductivity type (P/N) checker for quick check
- **Principle:** Photovoltaic effect by light pulse irradiation
- Instantly discrimination by optical pulse illuminate
- **Sample Size:** at least 30cm x 30cm
- **Resistivity Range (Ω .cm):** 0.1 to 1k



APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC etc)
- Oxidized film on wafer surface

PN CHECKER

PN-8LP PN CHECKER



- Single Point, Non-contact conductivity type (P/N) checker for quick check
- **Principle:** Photovoltaic effect with the 650nm laser diode
- **Power Supply:** 1.5VDC (size AA alkaline battery), 300mA
- **Judgement Display:** P(red) or N(green) LED lamps
- **Sample Size:** according to laser size
- **Resistivity Range (Ω .cm):** 0.1 to 2k (depending on sample surface condition)

APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC etc)

PN-100BI PN CHECKER

- Multi-Point, Non-contact Inline P/N checker module for Solar wafer
- **Principle:** Photovoltaic effect with the laser diode
- Suitable for production line and transportation system
- Connect to host PC by LAN to send measurement command and data
- **Sample Size:** 156mm x 156mm or 210mm x 210mm
- **Resistivity Range (Ω .cm):** 0.1 to 100



APPLICABLE MATERIALS

- Solar wafer